



PCN# : P56OAA
Issue Date : Jul. 06, 2015

DESIGN/PROCESS CHANGE NOTIFICATION

This is to inform you that a change is being made to the products listed below.

Unless otherwise indicated in the details of this notification, the identified change will have no impact on product quality, reliability, electrical, visual or mechanical performance and affected products will remain fully compliant to all published specifications. Products incorporating this change may be shipped interchangeably with existing unchanged products.

This change is planned to take effect in 90 calendar days from the date of this notification. Please work with your local Fairchild Sales Representative to manage your inventory of unchanged product if your evaluation of this change will require more than 90 calendar days.

Please contact your local Customer Quality Engineer within 30 days of receipt of this notification if you require any additional data or samples. Alternatively, you may send an email request for data, samples or other information to PCNSupport@fairchildsemi.com.

Implementation of change:

Expected First Shipment Date for Changed Product : Oct. 04, 2015

Expected First Date Code of Changed Product :1541

Description of Change (From) :
5-inch Wafer Fab at Fairchild Bucheon, Korea

Description of Change (To) :
8-inch Wafer Fab at Fairchild Bucheon, Korea

Reason for Change:
Improve supply flexibility
Better quality and yields through equipment and facility upgraded
Increased automation in handling and inspection in assembly
This is one of two PCNs being issued to replace cancelled PCN P4AOAA, to clarify the correct devices being fabricated in the 8-inch Wafer Fab Fairchild Bucheon, Korea

Affected Product(s): Please refer to the list of affected products in the addendum attached in the PCN email you received. This list is based on an analysis of your company's procurement history.

Qualification Plan	Device	Package	Process	No. of Lots
Q20140059	RHRG5060	TO247	Hyperfast	3

Test Description:	Condition:	Standard:	Duration:	Results:
High Temperature Reverse Bias	480V,175C	JESD22-A108	1000 hrs	0/231
High Humidity High Temp. Reverse Bias(H3TRB)	85%RH, 85C,100V	JESD22-A101B	1000 hrs	0/231
Autoclave	100%RH, 121C	JESD22-A102	96 hrs	0/231
Temperature Cycle	-55C,150C	JESD22-A104	1000 cyc	0/231
Power Cycle	On/Off=2.0min, Delta Tj=100C	MIL-STD-750 M1037	6000 cyc	0/77
High Temperature Storage Life	175C	JESD22-A103	1000 hrs	0/231

Qualification Plan	Device	Package	Process	No. of Lots
QP1411001	RURP15100_F085	TO220	Ultrafast	3

Test Description:	Condition:	Standard:	Duration:	Results:
High Temperature Reverse Bias	1000V,175C	JESD22-A108	1000 hrs	0/231
Highly Accelerated Stress Test	130C, 85%RH, 42V	JESD22-A110	96 hrs	0/231
Unbiased HAST	130C, 85%RH	JESD22-A118	96 hrs	0/231
Autoclave	100%RH, 121C	JESD22-A102	96 hrs	0/231
Temperature Cycle	-55C,150C	JESD22-A104	1000 cyc	0/231
Power Cycle	On/Off=5.0min, Delta Tj=100C	MIL-STD-750 M1037	6000 cyc	0/231
High Temperature Storage Life	150C	JESD22-A103	1000 hrs	0/231